



Applying visual variables to manufacturing data for enhanced decision-making

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Outline

- Visual variables & information visualization (InfoVis)
- Three visualization-related projects
 - Mapping MTConnect data to solid models
 - Exploring functional relationships of KPIs
 - Representing similarities for manufacturing processes
- Moving forward
 - Data Information Visualization & Exploration (DIVE) Lab

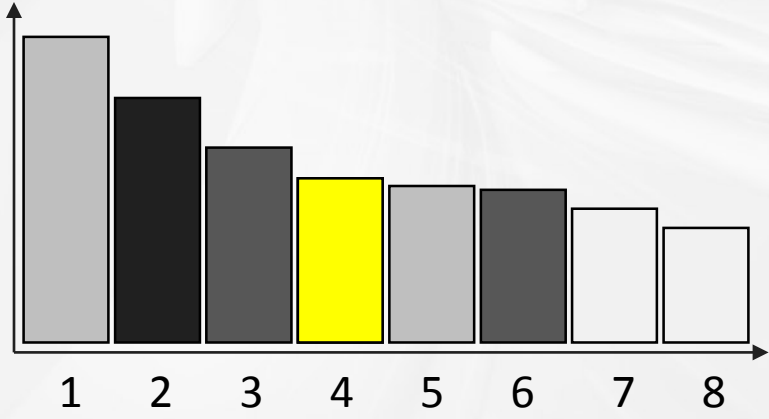
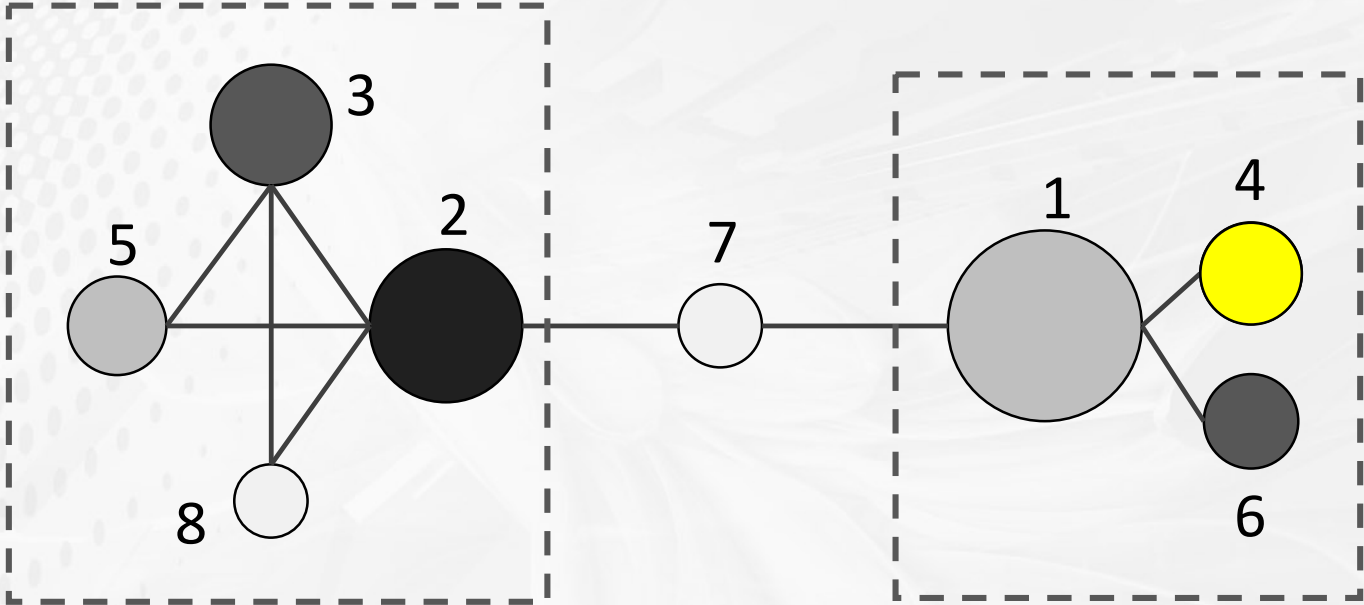


Outline



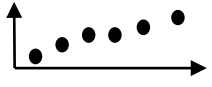



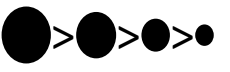
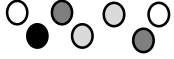

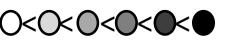



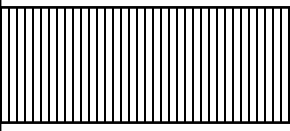

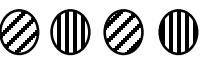
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Example



Selecting the right visual variable

		Characteristics				
		<i>Selective</i>	<i>Associative</i>	<i>Quantitative</i>	<i>Order</i>	<i>Length</i>
Visual Variables	<i>Position</i>					Theoretically Infinite
	<i>Size</i>					Selection: ~5 Distinction: ~20
	<i>Shape</i>					Theoretically Infinite
	<i>Value</i>					Selection: <7 Distinction: ~10
	<i>Color</i>					Selection: <7 Distinction: ~10
	<i>Orientation</i>					Theoretically Infinite
	<i>Texture</i>					Theoretically Infinite

Adapted from Prof. Sheelagh Carpendale, Dept. of CS, University of Calgary

Distilling design patterns

Goal: Suggest design patterns for InfoVis-based tools used in manufacturing

Task-by-type taxonomy	Example of design patterns for sustainable product design
T1: Overview	P1: Indicator-overviews P2: Eco-prominence P3: Eco-persistence
T2: Zoom	P4: Intent-based aggregation P5: Multiscale design exploration
T3: Filter	P6: Emphasis on design similarities P7: Collaborative pruning
T4: Details-on-demand	P8: Interactive detailing of hidden dimensions
T5: Relate	P9: Co-ordination of lifecycle views P10: Linking eco-indicators through the lifecycle
T6: History	P11: Eco-location P12: Shareable exploration trails
T7: Extract	P13: Exploration snippets



Outline

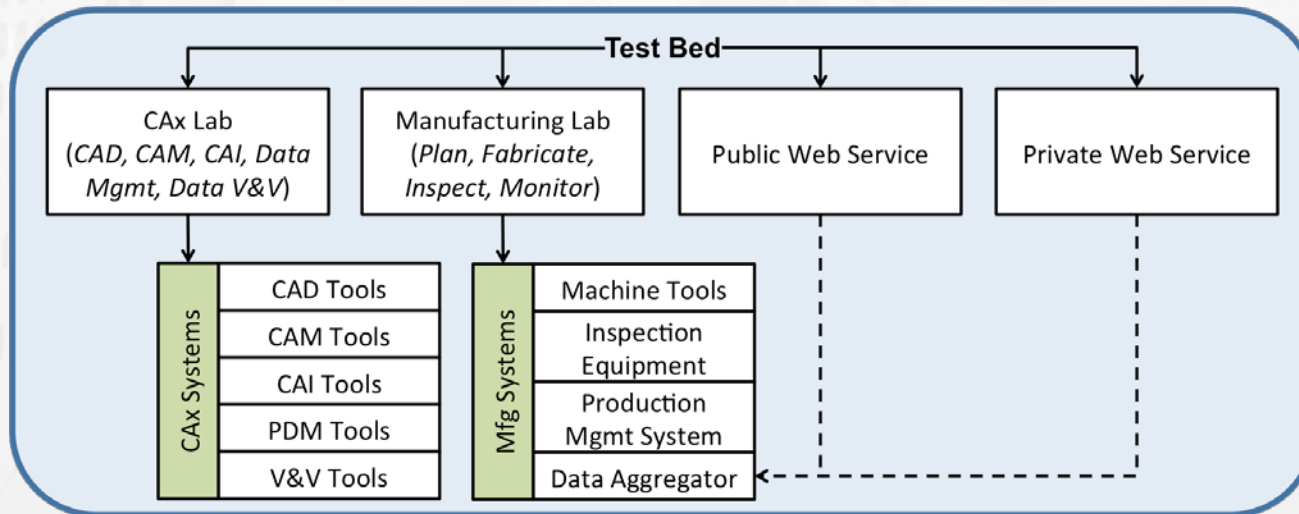
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NIST Smart Mfg. Systems Test Bed

Goals:

- Reference architecture and implementation
- Rich source of data for fundamental research
- Physical infrastructure for standards and technology development
- Demonstration test cases for education



<http://smstestbed.nist.gov>

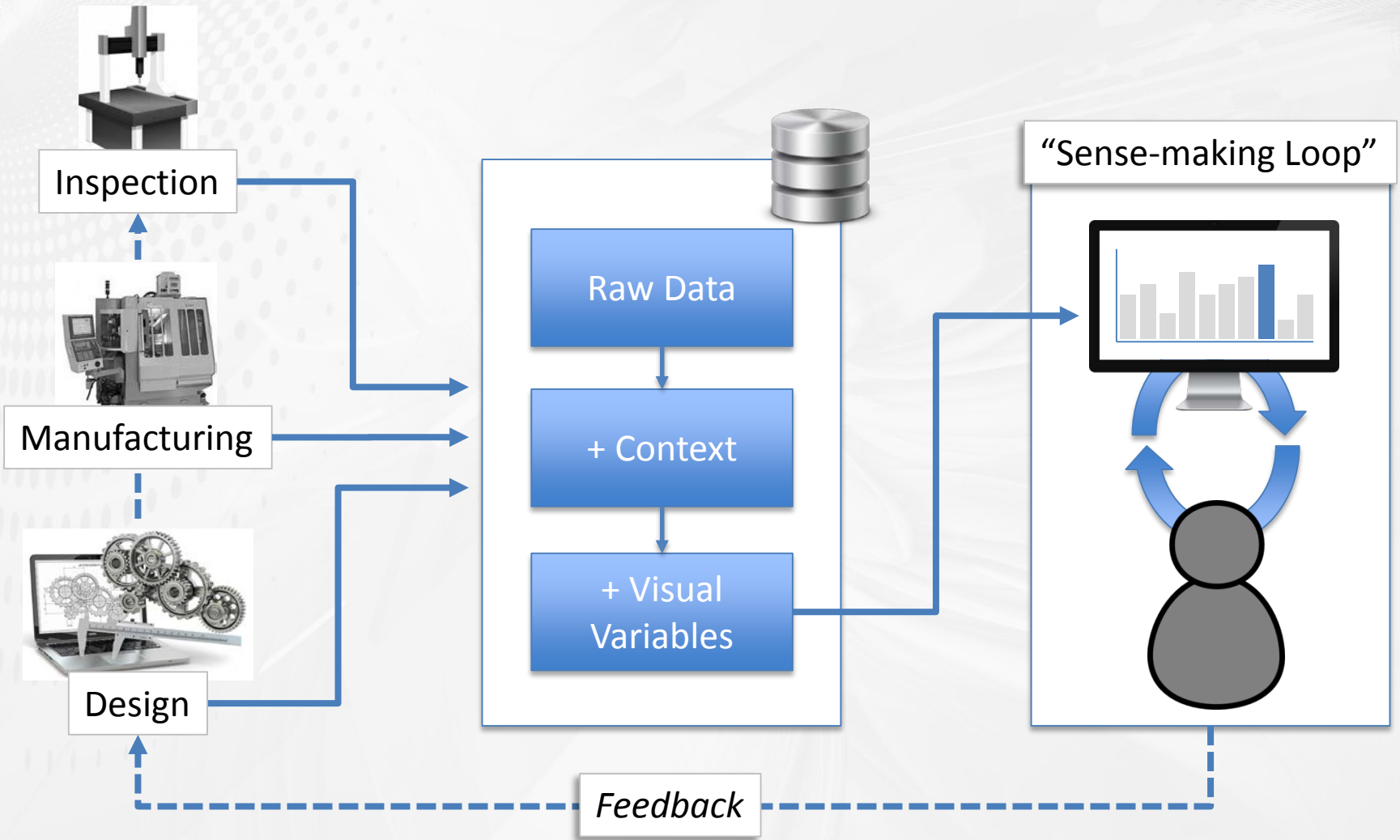


Available data

- Design model data in native and STEP standard format (***as designed***)
- Milling program as NC code in ISO 6983 standard format (***as planned***)
- Manufacturing execution data in MTConnect standard format (***as executed***)
- Inspection data in QIF standard format (***as inspected***)

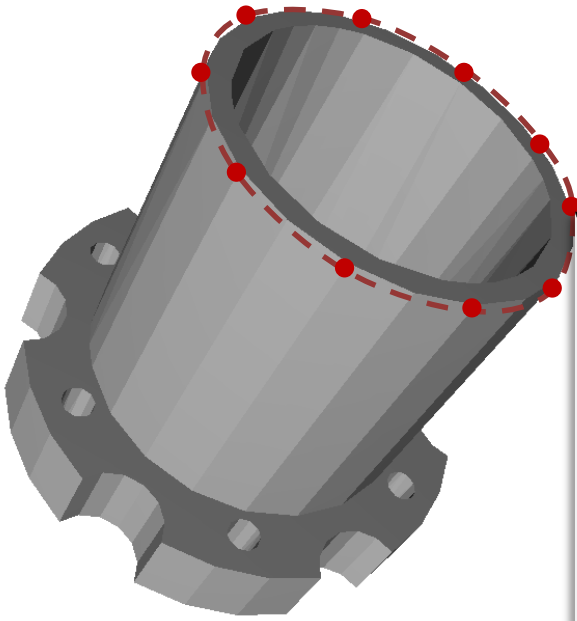


Visualization pipeline for smart manufacturing



Mapping machine data w/ virtual models

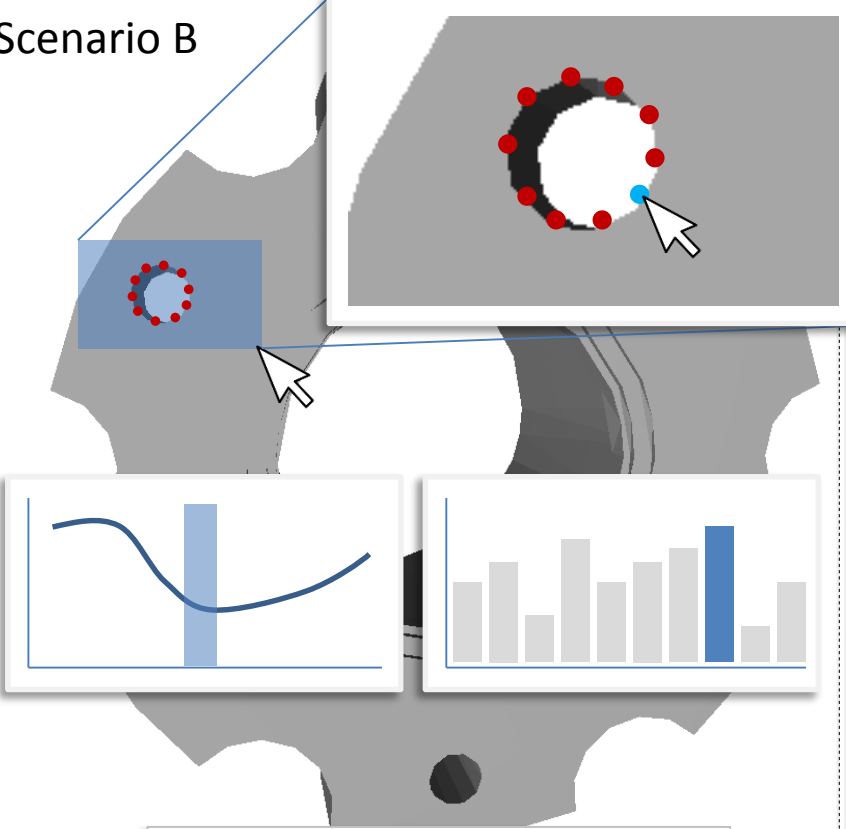
Scenario A



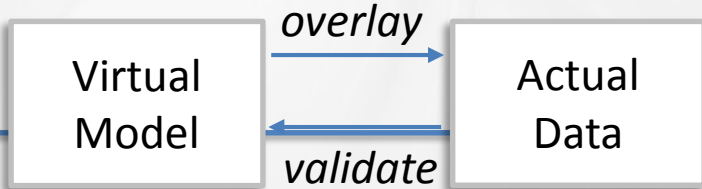
Oct 27, 2015 (16:42.31)
Cdeg: 156.9984
Cfrt: 0.588225
Sprm: 0
S2rpm: 304
Xabs: 42.242486
Xfrt: 10.93047
Zabs: 1.50241
Zfrt: 9.901767
Fact: 904.8242
Sovr: 150
Fovr: 50
Frapidovr: 25

Time Snapshot Visualization

Scenario B

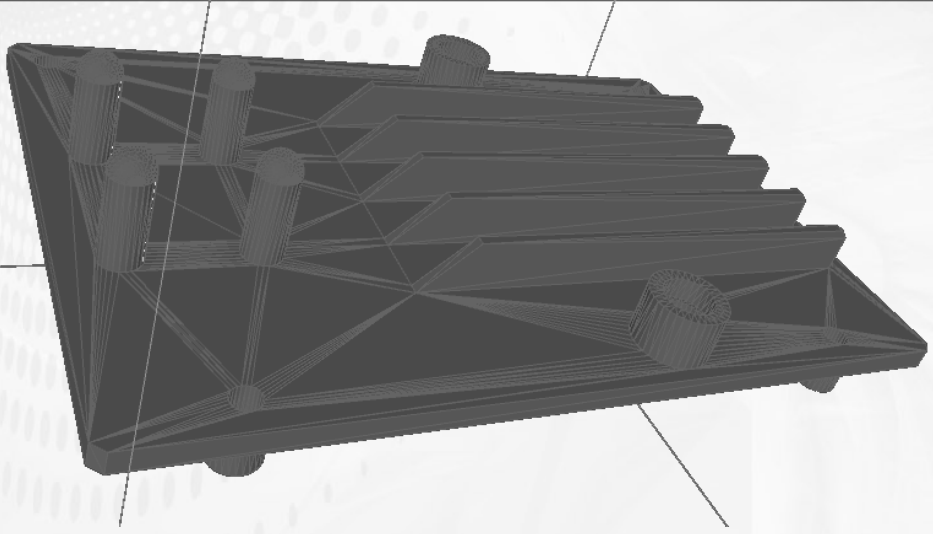


Feature-level Data Retrieval



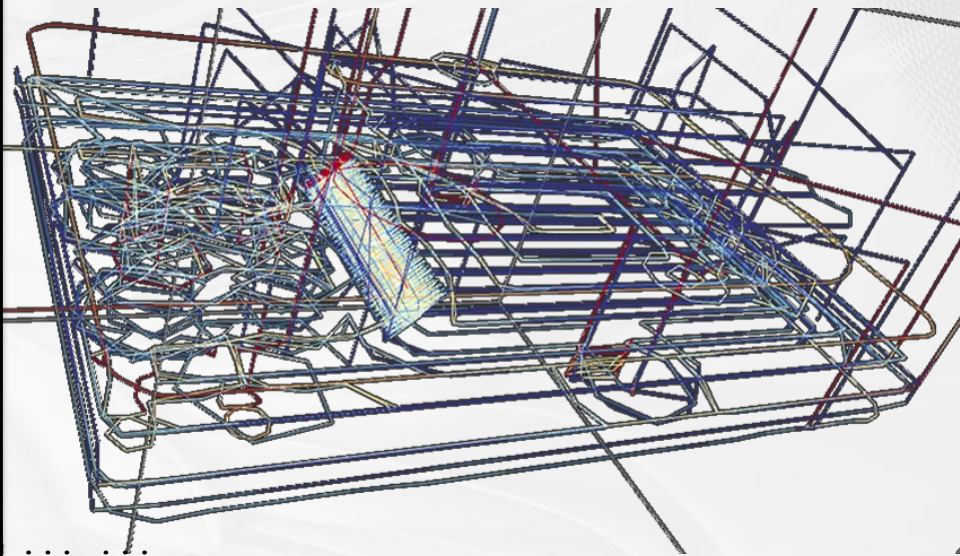
Standard representations of design and manufacturing data

Design Data



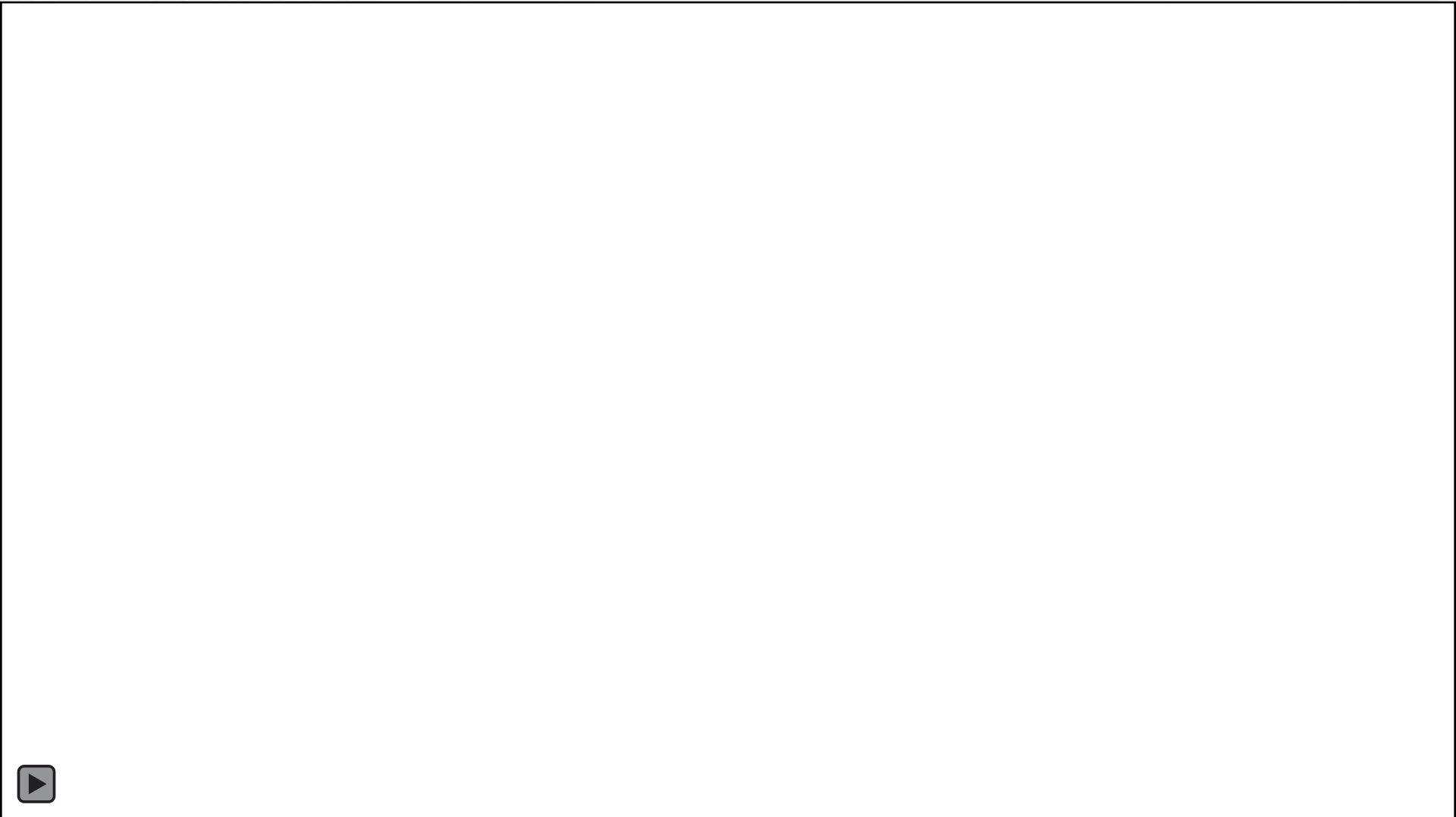
```
... ..  
#131=DIRECTION(' ',(1.,0.,0.));  
#136=AXIS2_PLACEMENT_3D(' ',#126,#121,#131);  
#141=PLANE(' ',#136);  
#146=CARTESIAN_POINT(' ',(-8.361367154208E-16...  
#151=DIRECTION(' ',(1.087705058168E-16,1.,0.));  
#156=VECTOR(' ',#151,1.);  
#161=LINE(' ',#146,#156);  
#166=CARTESIAN_POINT(' ',(-8.361367154208E-16...  
#167=VERTEX_POINT(' ',#166);  
... ..
```

Manufacturing Data



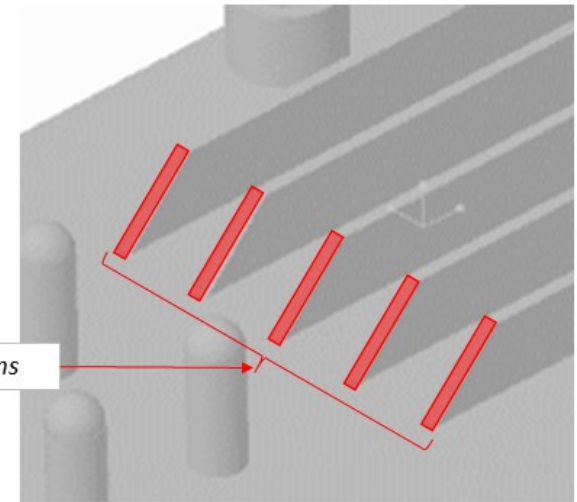
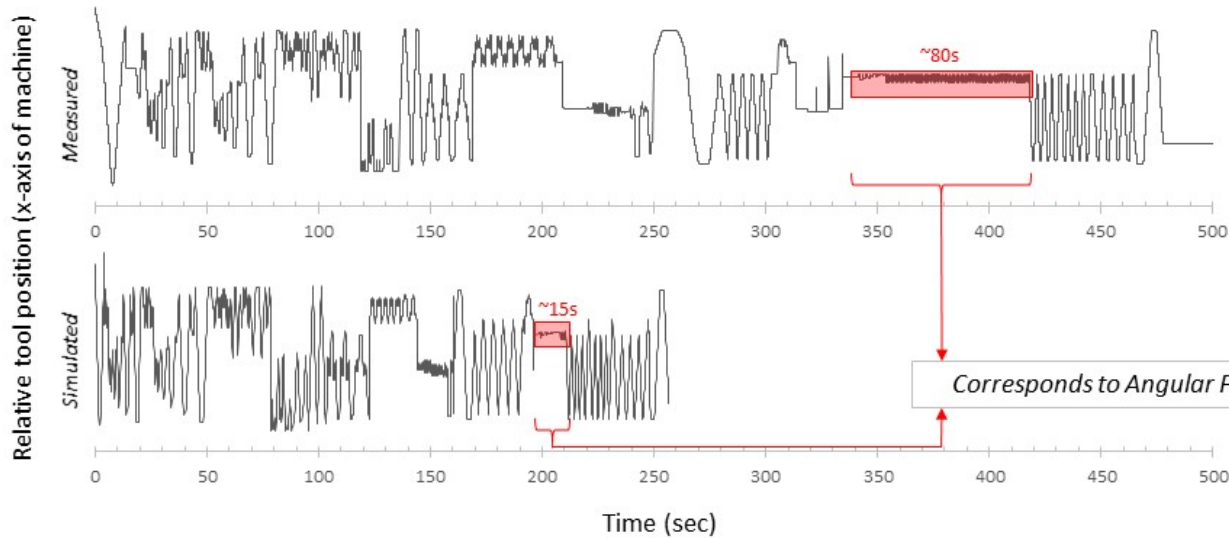
```
... ..  
2016-05-09T11:46:51.456188Z|path_pos|15.0998...  
2016-05-09T11:46:51.608005Z|path_pos|15.0998...  
2016-05-09T11:46:51.752206Z|path_pos|15.0998...  
2016-05-09T11:46:52.040056Z|path_pos|15.0998...  
2016-05-09T11:46:52.040278Z|Cposition|359.9848  
2016-05-09T11:46:52.184104Z|Cposition|359.9847  
2016-05-09T11:46:52.616003Z|path_pos|15.0998...  
2016-05-09T11:46:52.616184Z|Yposition|-37.80295  
2016-05-09T11:46:52.760205Z|path_pos|15.0998...  
... ..
```

Video: Initial prototype



Knowledge generated from case study

- Expected cycle time for one feature was 15 seconds, but measured results show actual time was 80 seconds
- Feed rate mismatch affects production schedule



Retrieve models and data at: <http://smstestbed.nist.gov/tdp/d2mi>



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Background – ISO 22400

KPI description	
Content	
Name	Overall equipment effectiveness index
ID	
Description	The OEE index represents the availability of a work unit (see Table 9), the effectiveness of the work unit (see Table 10), and the quality ratio (see Table 11) KPIs integrated in a single indicator.
Scope	Work unit, product, time period, product, defect types
Formula	OEE index = Availability * Effectiveness * Quality ratio
Unit of measure	%
Range	Min: 0% Max: 100%
Trend	The higher, the better
Context	
Timing	On-demand, periodically, real-time
Audience	Operator, supervisor, management
Production methodology	Discrete, batch, continuous
Effect model diagram	See Figure A.6
Notes	<p>Overall equipment effectiveness (OEE) is an indicator for the efficiency of work units, work centres and areas with several work units or an entire work centre. The OEE index forms the basis for improvements by better production information, identification of production losses, and improvement of the product quality by optimized processes.</p> <p>The calculation of OEE based on the hierarchy structure (see Figure 2) is only useful if the characteristic of the work unit processes would be comparable. Before starting a benchmark based on the OEE index the criteria for comparability should be checked.</p>



Background

$$\text{Overall Equipment Effectiveness} = \text{Availability} \cdot \text{Effectiveness} \cdot \text{Quality Ratio}$$

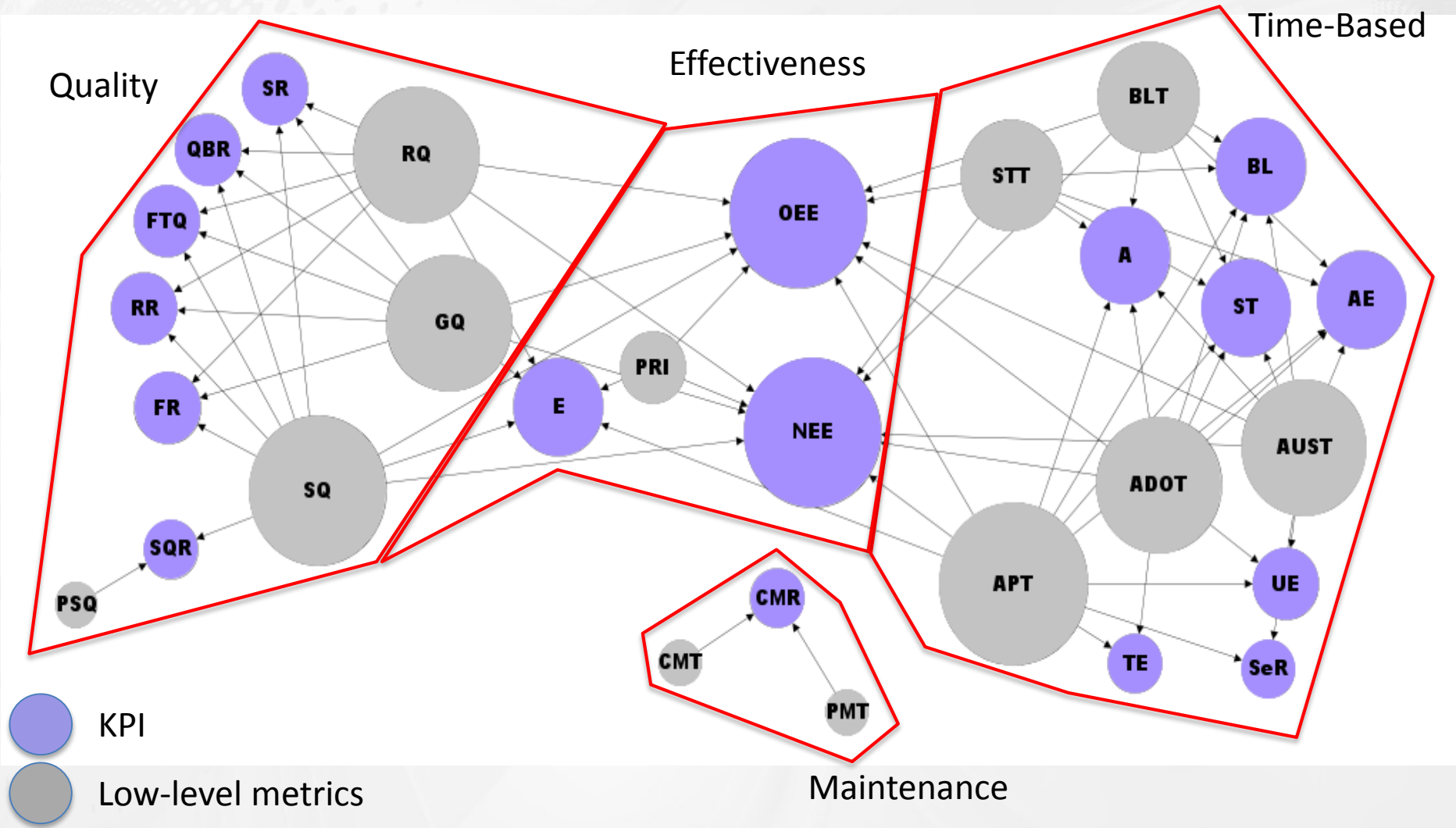
$$\text{Availability} = \frac{\text{Actual Production Time}}{\text{Planned Busy Time}}$$

$$\text{Effectiveness} = \frac{\text{Planned Run time per Item} \cdot \text{Produced Quantity}}{\text{Actual Production Time}}$$

$$\text{Quality Ratio} = \frac{\text{Good Quantity} + \text{Rework Quantity}}{\text{Produced Quantity}}$$



Node-Link Diagrams



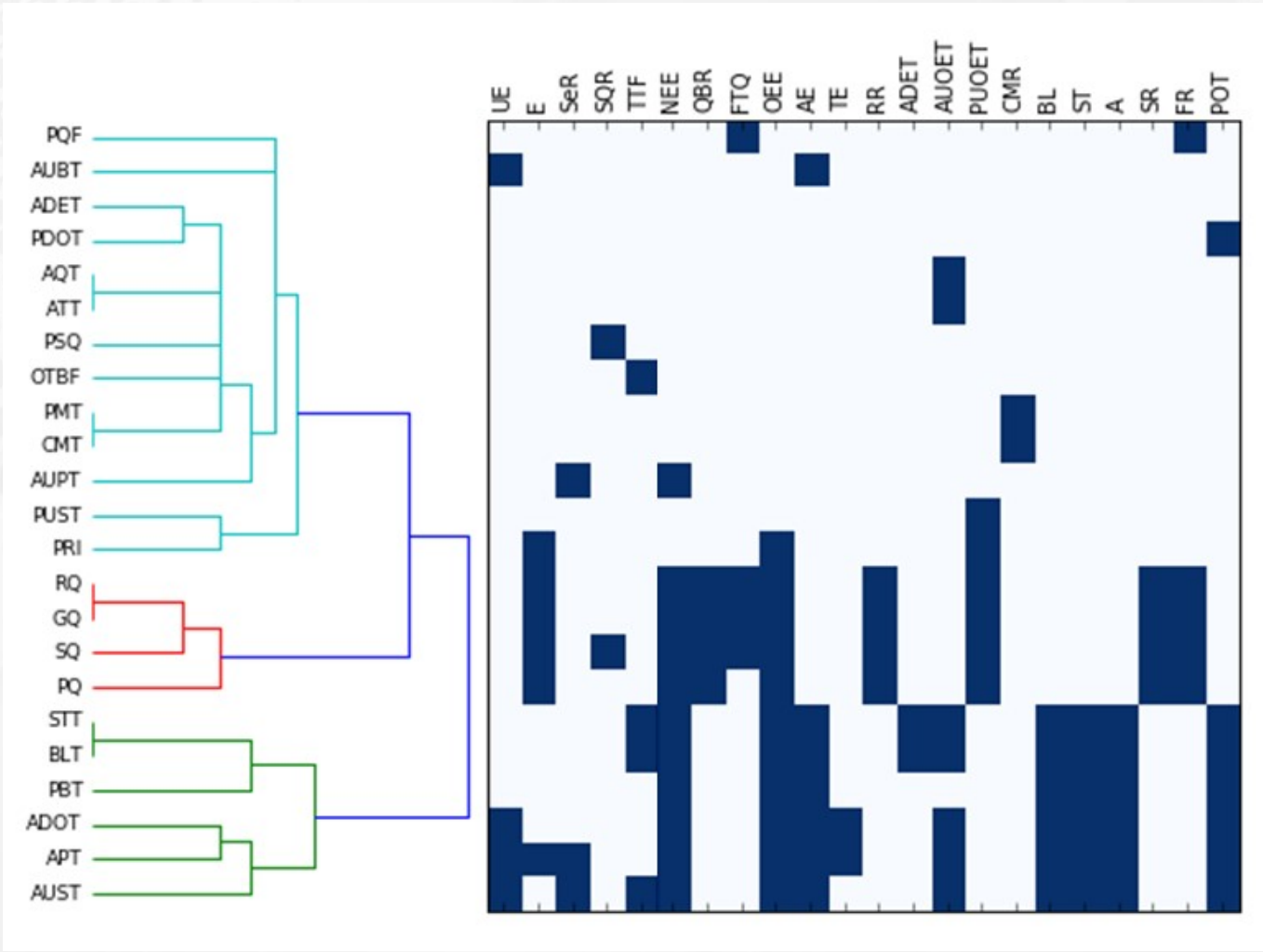
Time-Based

Maintenance

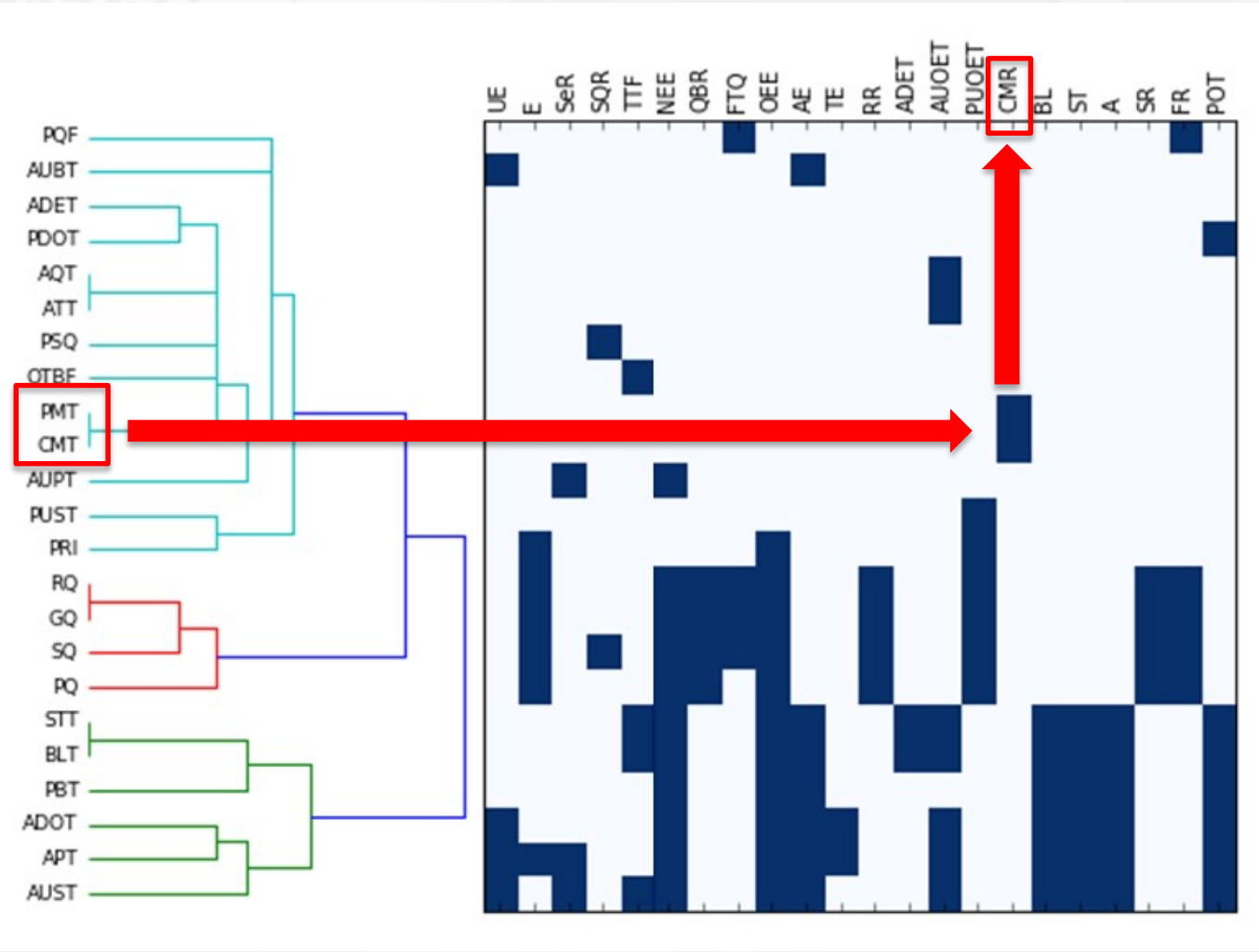
Brundage, MP, Bernstein, WZ, Morris, KC, Horst, JA. Graph-based Visualizations to Explore KPI Relationships. *Proceedings of the CIRP LCE 2017*. To appear.



Matrix-based visualization

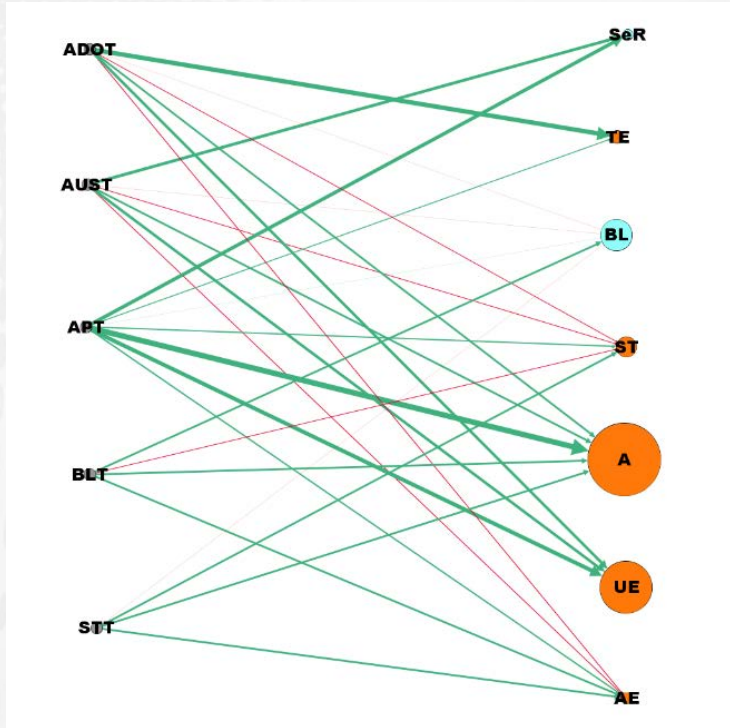


Matrix-based visualization



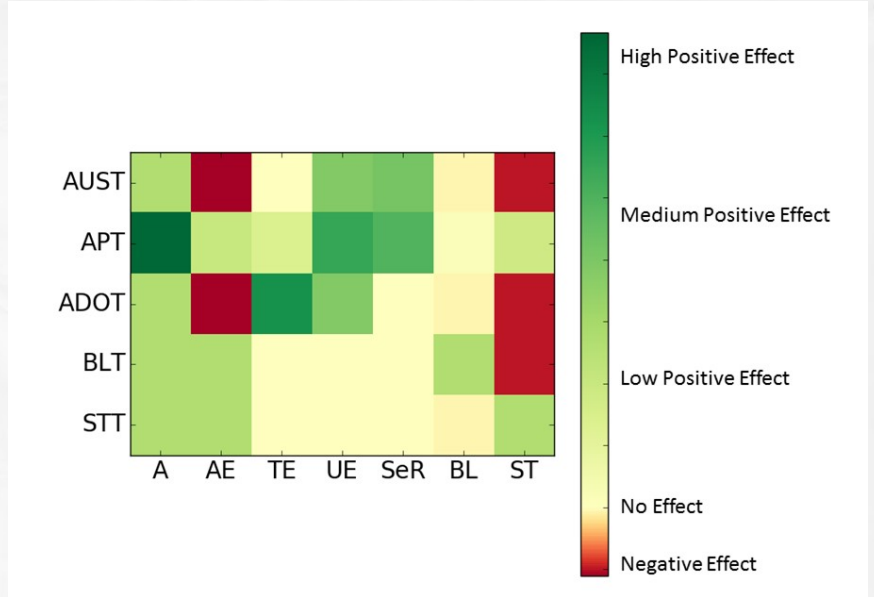
Exploring “what-if” scenarios

Node Link



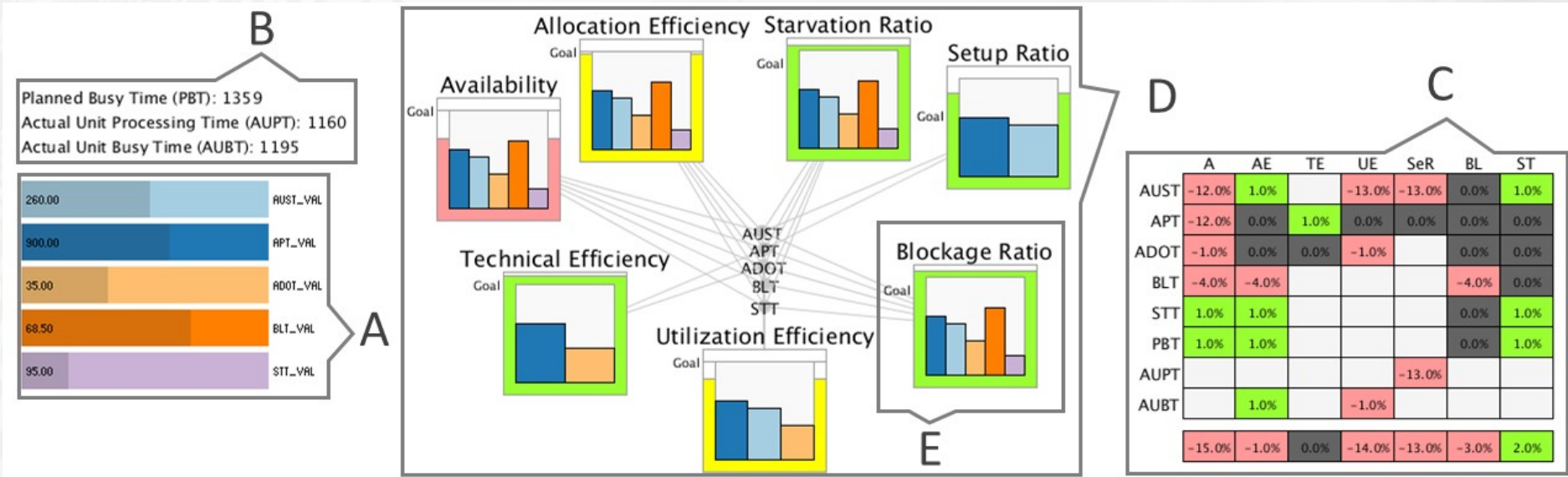
Line Thickness show change
Quickly shows KPI performance

Matrix Based



Color map shows change
Only shows change in KPIs with changing metrics

Prototype interface



(A) Control sliders

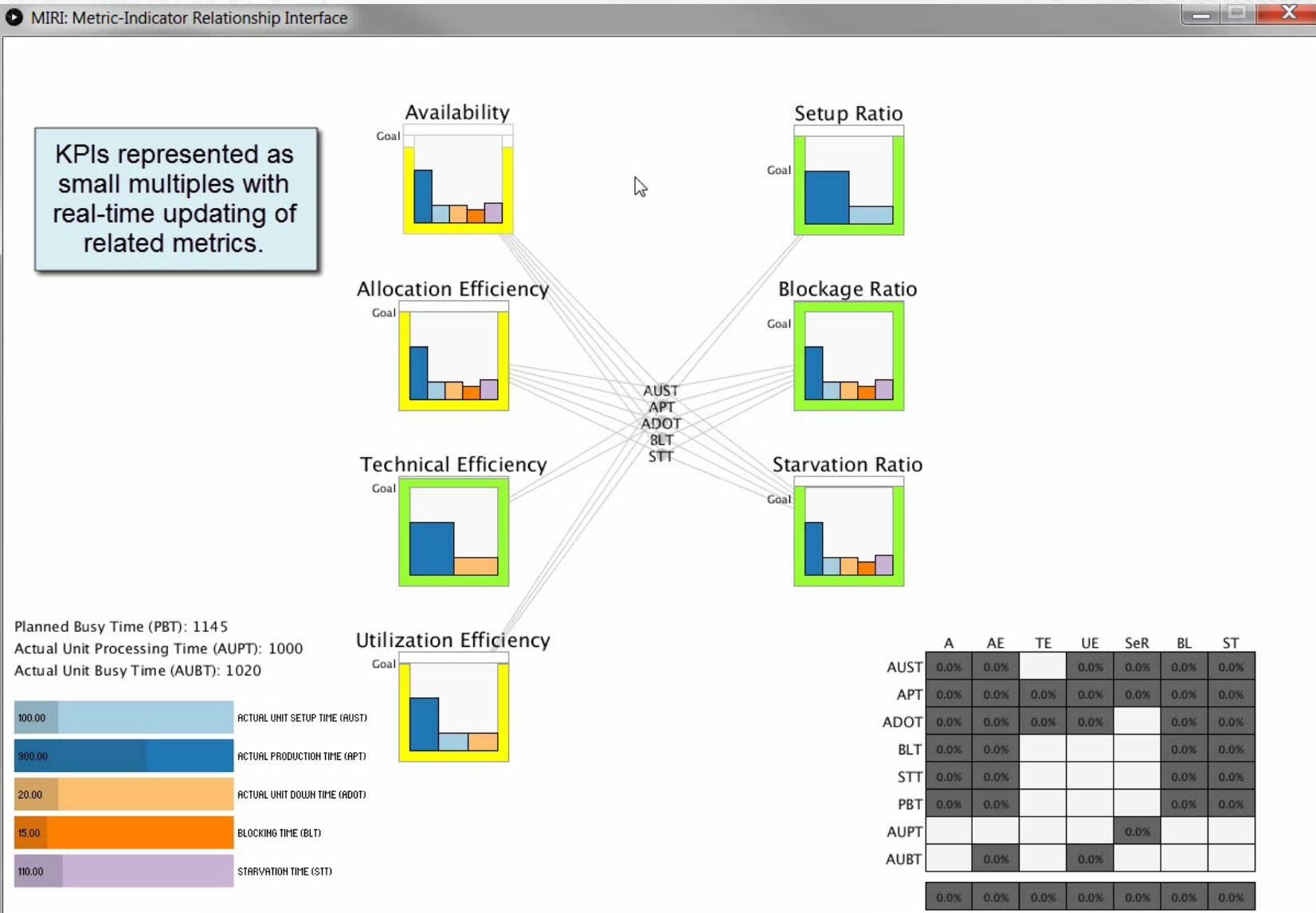
(D) Node-link diagram

(C) Sensitivity matrix

(B) Dependent metric readout

(E) Small multiples, i.e. nodes

Video: Initial prototype



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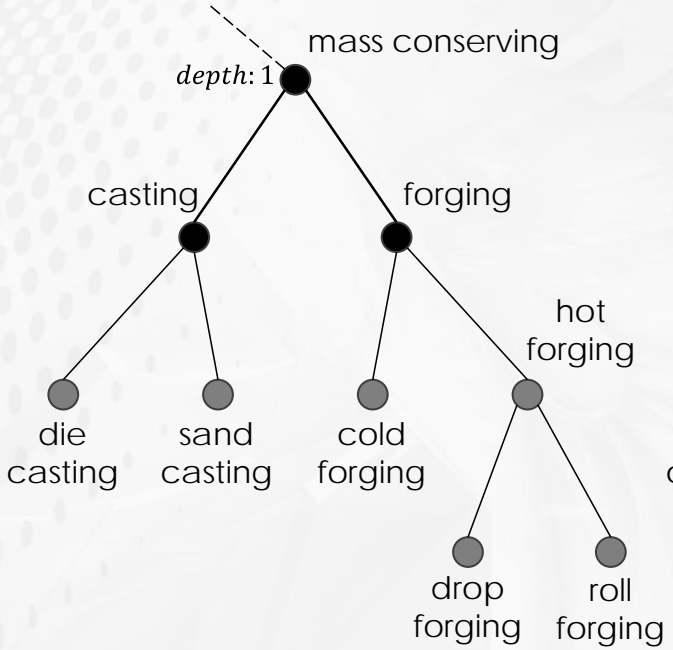


Guiding questions

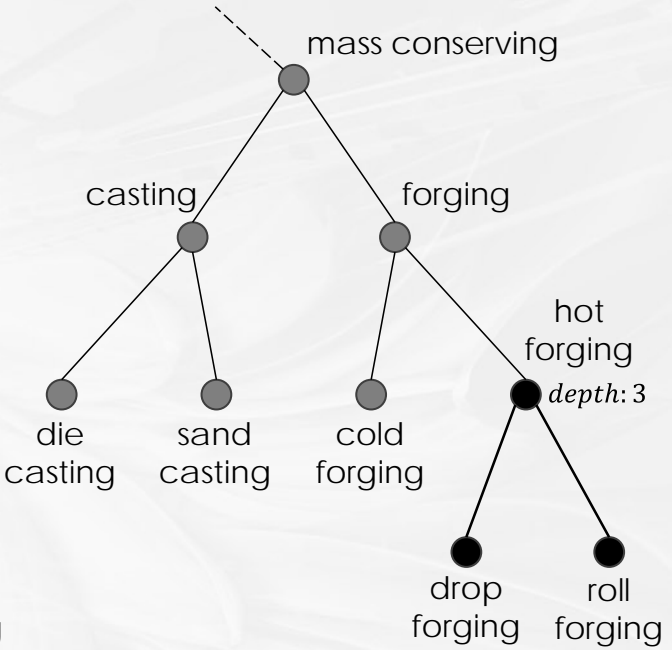
- How can we visualize the similarities of capabilities of manufacturing processes?
- How can we use these principles for better lookup in a large database?



Similarity based on taxonomic representation



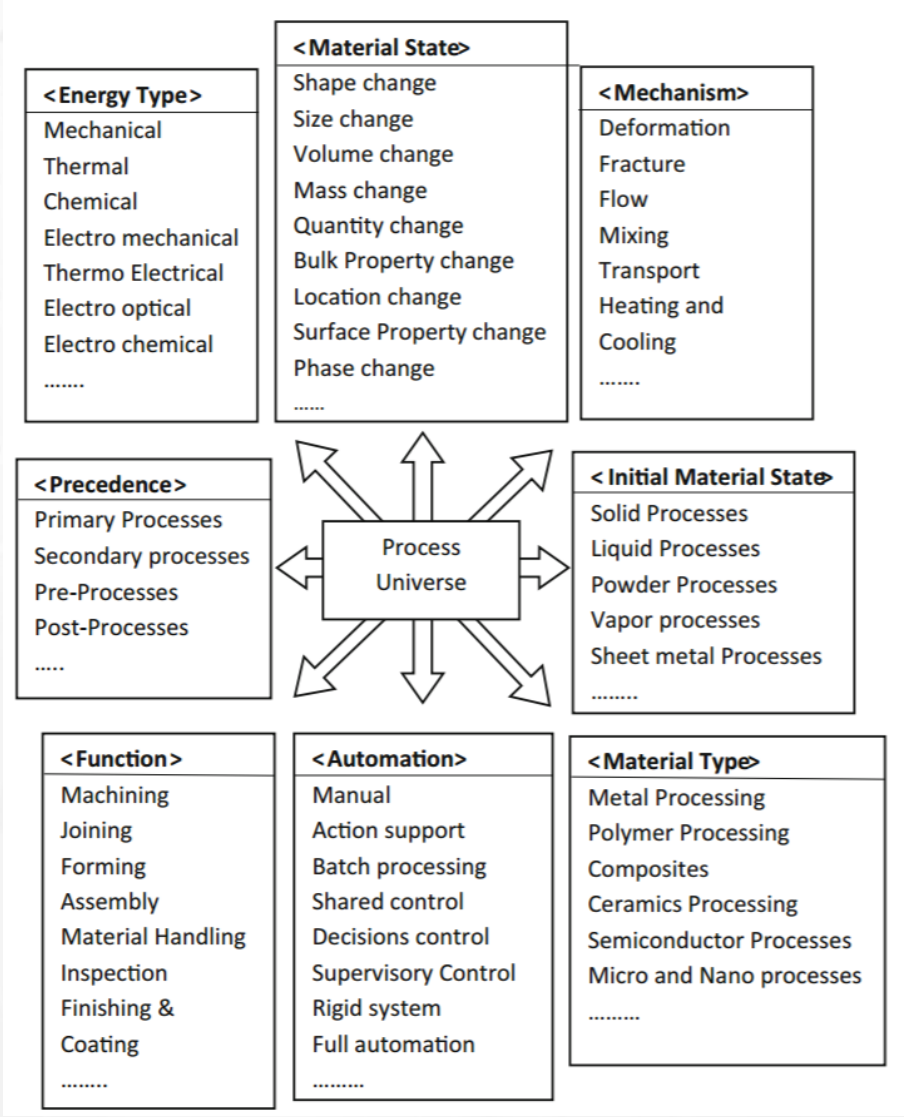
$$D(\text{casting}, \text{forging}) = \frac{2}{2 + (1 * 1)}$$



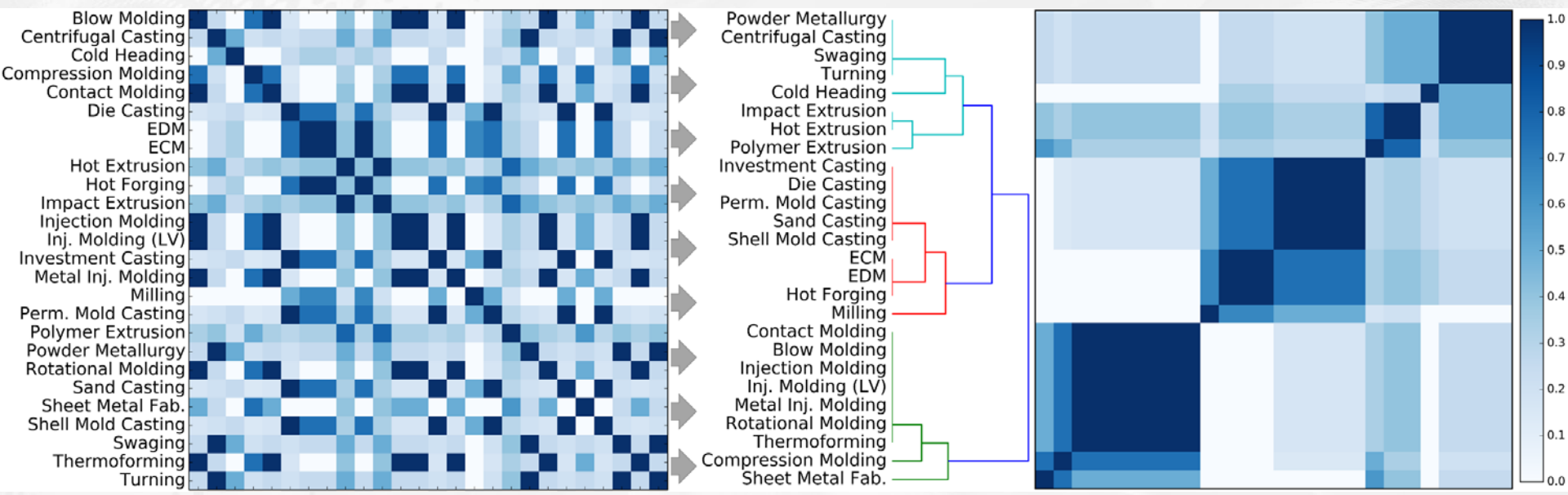
$$D(\text{drop forging}, \text{roll forging}) = \frac{2}{2 + (1 * 3)}$$

$$D(a_1, a_2) = \frac{\text{pathlength}(a_1, a_2)}{\text{pathlength}(a_1, a_2) + (k * \text{depthLCA}(a_1, a_2))}$$

Classification of Manufacturing Processes



Visualizing similarities of manufacturing processes

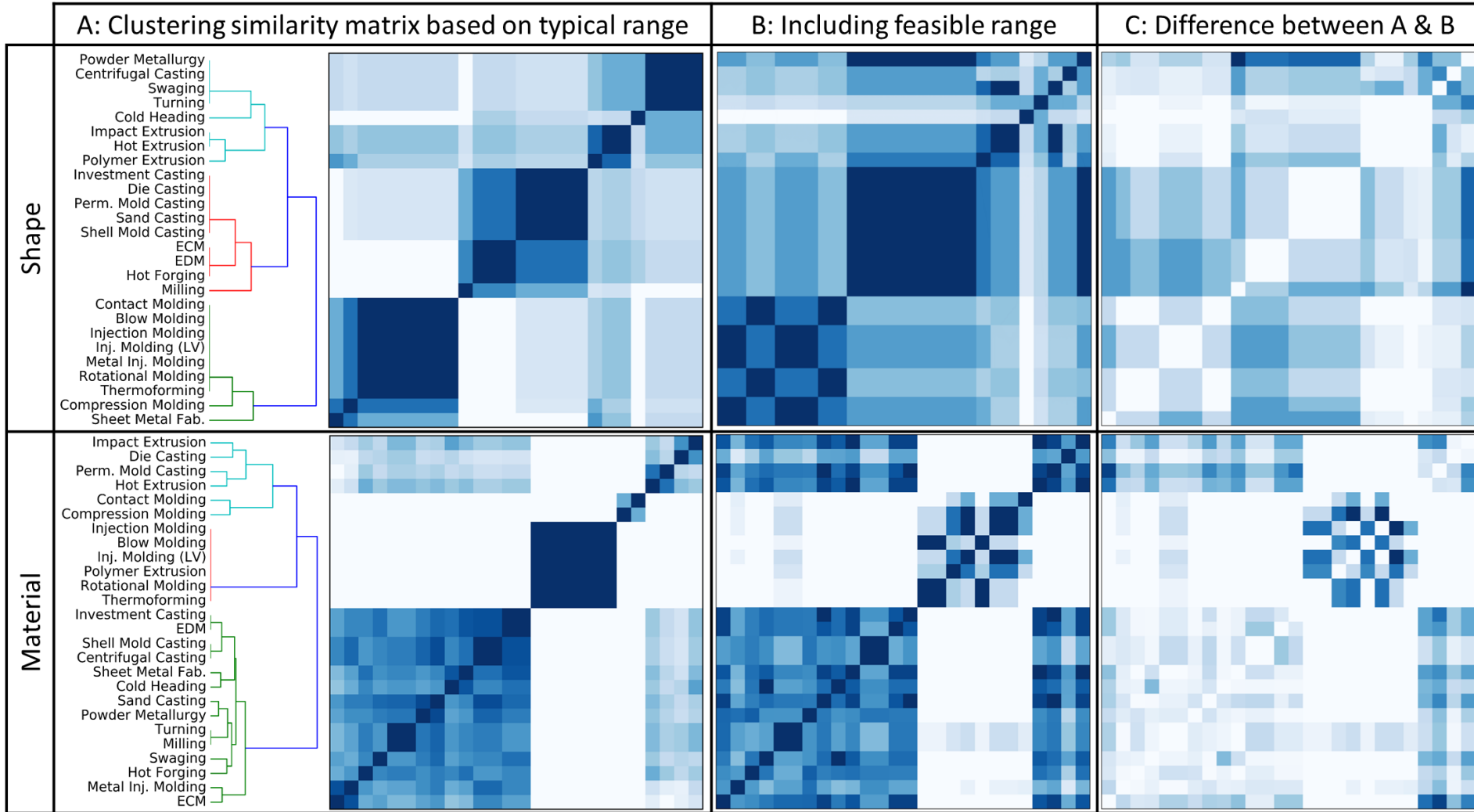


Example:

Blow Molding → {"Thin-walled: Cylindrical"; "Thin-walled: Cubic"; "Thin-walled: Complex"}

Die Casting → {"Thin-walled: Complex"; "Solid: Cylindrical"; "Solid: Cubic"; "Solid: Complex"}

Visualizing similarities of manufacturing processes



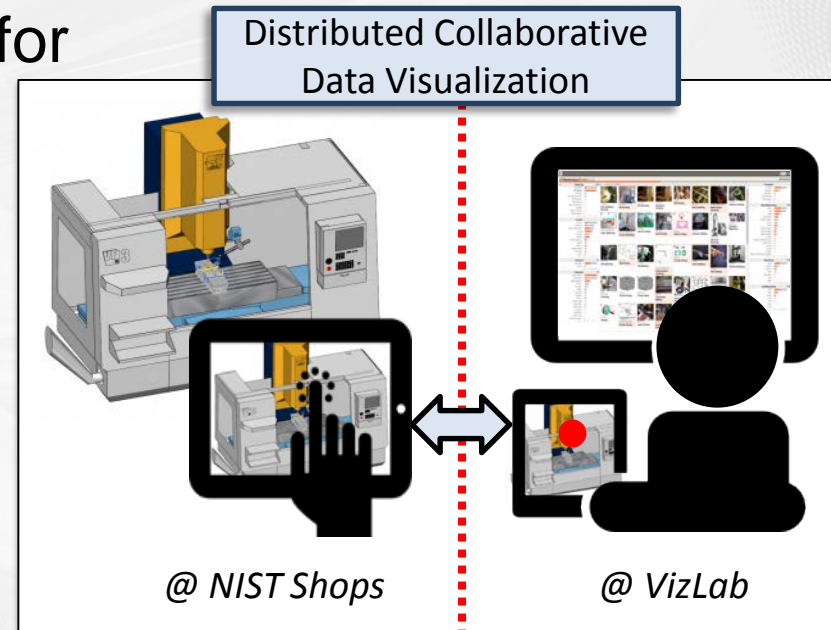
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Data Information Visualization & Exploration Lab

- Demonstrate practical use cases for data exploration
- Identify and demonstrate “design patterns” for mfg-based visualizations
- Quicken the design, prototyping and implementation of new interfaces



Hardware & software considerations

Hardware options:

- MSFT Surface Hub
- CINTIQ Pen & Touch
- Intuous Pen & Touch
- MSFT Kinect
- Tablets, etc.
- VR

*Interact with NIST Library

Software options:

- Open: Cytoscape, JigSaw, NodeXL, Processing 3, Gephi, Keshif.js
- Commercial: Power BI, Tableau, IBM Watson

Middleware options:

- Open: libavg, Polychrome, Webstrates, Sage II



Thank you!

**Questions?
Comments?
Suggestions?**

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